U.S. DEPAI PATENT AI PATENT AI PATENT AI U.S. DEPAI PATENT AI Form PT 049P U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE ATTY. DOCKET NO. MI22-2430 SERIAL NO. 10/705,371 **APPLICANT** Brian E. Cron **FILING DATE GROUP** Nov. 10, 2003 [RCE filed herewith] 3723 U.S. PATENT DOCUMENTS Document Date Class Subclass Filing Date If Appropriate Number AA 6,740,247 B1 05/04 Han et al. ΑВ 08/04 Nishimura et al. 6,776,691 B2 AC ΑD ΑE AF AG AH AI AJ AK AL FOREIGN PATENT DOCUMENTS Document Number Date Country Subclass Translation Yes No AN ΑP AQ OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AR A\$

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

DATE CONSIDERED

Form POVE E

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2430

SERIAL NO. 10/705,371

APPLICANT

FOR ART CITED BY APPLICANT (Use several sheets if necessary) Brian E. Cron GROUP FILING DATE Nov. 10, 2003 [RCE filed herewith] 3723 U.S. PATENT DOCUMENTS Subclass Class Filing Date If Appropriate *Examiner Initial Document Number Date Name 2003/0217762 A1 AA 11/03 Kobayashi et al. AB AC AD ΑE AF AG AH Al Aj AK AL FOREIGN PATENT DOCUMENTS Document Date Country Class Subclass Translation Number Yes No AM AN ΑO ΑP AQ OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AR AS AT EXAMINER ///hony DATE CONSIDERED)lini

"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

EN550717305										
				DEPARTMENT OF COMMERCE ATTY, DOCKET MIZZ-2430		NO.		SERIAL NO	SERIAL NO. 10/705,371	
PATENT AND TRADEMARK OFFICE USE OF ART CITED BY APPLICANT Same several shoots if necessary)					APPLICANT Brian E. Cron					
) \a_					FILING DATE Nov. 10, 2003 [RCE filed herewith]			GROUP 3723		
Vin	TE TRA	DEMAR		U.S. PATENT DOCUMENTS						
Examiner Initial	er Document		Oato	Name		Class	Subclass	s Filing Date If Appropriate		
AD	•	6,332,835 B1	12/01	Nishimura et al.		-				
	AB									
	AC									
	AD									
	Æ									
	AF									
	AG									
	AH				•					
	Al								-	
	AJ		·					-		
	AK				•					
	AL									
FOREIGN PATENT DOCUMENTS										
		Document Number	Date	Country		Class	Subclass			
	AM							Yes_	No	
	AN									
	AO									
	AP		<u> </u>	 						
AQ OTHER REFERENCES (Including Author, Title, Date, Pertinant Pages, Etc.)										
	AR		- <u>-</u>		·					
	AS									
	AT									
Examiner Dini Date considered 6/21/05										
*EXAMPLER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										